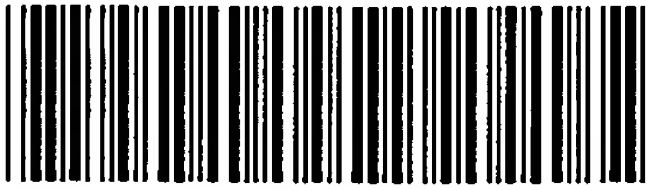


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/620,126	KRUCK, STEFAN	
	Examiner	Art Unit	
	Aaron M. Dunwoody	3679	

SEARCHED			
Class	Subclass	Date	Examiner
285	401,327	5/29/2006	AMD

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR